

<b>Notice of References Cited</b>	Application/Control No. 10/761,993	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner DuyVu n. Deo	Art Unit 1765	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,653,203	11-2003	Huang et al.	438/435
	B	US-6,787,409	09-2004	Ji et al.	438/221
	C	US-2004/0077163	04-2004	Chang et al.	438/689
	D	US-6,180,492	01-2001	Shih et al.	438/435
	E	US-6,555,442	04-2003	Pai et al.	438/424
	F	US-6,191,004	02-2001	Hsiao, Chih-Hsiang	438/435
	G	US-6,146,974	11-2000	Liu et al.	438/435
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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